Docket No.: PHCF-03037US

HIR.130

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Rec'd PCT/PTO 2 7 DEC 20

In re patent application of

Masatomo Shibata, et al.

Serial No.:

Not Yet Assigned

Group Art Unit:

Not Yet Assigned

Filing Date:

Concurrently Herewith

Examiner:

Unknown

For:

POROUS SUBSTRATE AND FABRICATION METHOD THEREFOR, AND GaN SERIES SEMICONDUCTOR LAYERED SUBSTRATE AND

FABRICATION METHOD THEREFOR

Honorable Commissioner of Patents Alexandria, Virginia 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

Under the provisions of 37 CFR §1.97 through §1.99 and pursuant to applicant's duty of disclosure under 37 CFR §1.56, applicant respectfully brings the following documents listed on the attached form PTO-1449 and some of which are cited in the International Search Report (Form PCT/ISA/210), to the attention of the Examiner in charge of the above-identified application. Copies of the listed documents are provided herewith for the convenience of the Examiner. Further, in compliance with the concise explanation requirement under 37 CFR §1.98(a)(3) for foreign language documents the relevance of these documents is discussed on pages 2 and 3 of the subject application. Further, for foreign documents English-language Abstract are attached.

This citation does not constitute an admission that the references are relevant or material to the claims. They are only cited as constituting related art of which the applicant is aware.

It is respectfully requested that the listed references be considered by the Examiner and formally made of record in this application.

Please charge any deficiencies in fees and credit any overpayment of fees to Attorney's Deposit Account No. 50-0481.

Respectfully submitted,

Sean M. McGinn, Esq. Registration No. 34,386

Date: \\\ \(\frac{7}{\lambda} \) \(\lambda \) \(\lambda

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DT05 Roc'd PCT/PT

Docket Number (Optional)

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Applicant(s)

Masatomo Shibata, et al.

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U.S. PATENT DOCUMENTS

INFORMATION DISCLOSU

(Use several sheets if necessary)

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*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS SUBCLASS		FILING DATE IF APPROPRIATE	
		5,656,832	08/12/1997	Ohba et al.				

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FOREIGN PATENT DOCUMENTS

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		EP 1 271 627 A2	01/02/2003	Japan				
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		GB 2 344 461 A	06/07/2000	Japan				
		2-81484	03/22/1990	Japan				

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

Chinkyo Kim, et al., "Relaxation of anisotropic domain tilting along vertical growth direction in selectively lateral overgrown GaN by hydride vapor phase epitaxy", Journal of Crystal Growth 208, 2000, pp. 804-808.

P. Fini, et al., "In sity, real-time measurement of wing tilt during lateral epitaxial overgrowth of GaN", Applied Physics Letters, Volume 76, Number 26, June 26, 2000, pp. 3893-3895

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-A820 (also form PTO-1449) P09A/REV05

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Docket Number (Optional) PHCF-03037US

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Masatomo Shibata

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ATTY DOCKET NO.

PHCF-03037

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APPLICANT(S)

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